



IFW
Docket No.: SON-2920
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Hironori Ibusuki

Art Unit: 1756

Application No.: 10/780,667

Conf. No. 1986

Filed: February 19, 2004

For: **EXPOSURE PATTERN OR MASK AND
INSPECTION METHOD AND
MANUFACTURE METHOD FOR THE SAME**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the information item(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each item(s) is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the item(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date or the date of filing a CPA, OR (b) before the mailing date of a first Office Action on the merits in the present application, or (c) accompanies a Request for Continued Examination.

a. I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a Search Report issued from a corresponding application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).

2. This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection or Notice of Allowance.

- a. I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a Search and Examination Report issued from a corresponding application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).
- b. I hereby certify that no item of information in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(2).
- c. Please charge our Deposit Account No. 18-0013 the \$180.00 fee and charge any additional fee or credit any overpayment to Deposit Account No. 18-0013 as needed to ensure consideration of the disclosed information.

3. This Information Disclosure Statement is being filed more than three months after the U.S. filing date and after the mailing date of a Final Rejection or Notice of Allowance, but before payment of the Issue Fee. Applicant(s) hereby petition(s) that the Information Disclosure Statement be considered. Please charge our Deposit Account in the amount of \$180.00 in payment of the petition fee under 37 CFR §1.17(i)(1). Please charge any fee deficiency or credit any overpayment to Deposit Account No. 18-0013 as needed to ensure consideration of the disclosed information.

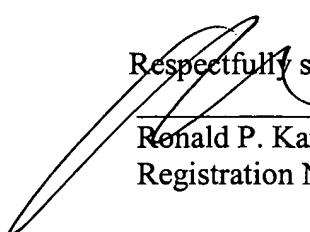
- a. I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a corresponding foreign application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).
- b. I hereby certify that no item of information in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to my knowledge after making reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(2).

4. The references were cited at page 2 of the specification.

5. In the event any fees are due with this paper, please charge our Deposit Account No. 18-0013.

Date: July 1, 2004

Respectfully submitted,


Ronald P. Kananen
Registration No. 24,104

Rader, Fishman & Grauer PLLC
1233 20th Street, N.W.,
Suite 501
Washington, D.C. 20036
Tel: (202) 955-3750
Fax: (202) 955-3751



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Substitute for form 1449A/B/PTO				Complete If Known	
				Application Number	10/780,667
				Filing Date	February 19, 2004
				First Named Inventor	Hironori Ibusuki
				Art Unit	1756
				Examiner Name	N/A
Sheet	1	of	1	Attorney Docket Number	SON-2920

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
AA	5,831,272		11/3/98	Utsumi	
AB					

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
	CA	EPL: Electron-beam Proximity Lithography, "Projection Exposure with Variable Axis Immersion Lenses: A High-Throughput Electron Beam Approach to Suboptical Lithography" H.C Pfeiffer, Jpn. J. Appl. Phys. Vol. 34 (1995) pp. 6658-6662			
	CB	LLEEPL: Low Energy Electron-beam Proximity Projection Lithography, "Characterization of a Process Development Tool for Ion Projection Lithography, Hans Loeschner, et al, J.Vac. Sci. technol. B19, (2001)			
	CC				
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Examiner Signature		Date Considered	
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